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Substitute for form 1449A/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)				Complete if Known	
				Application Number	Based on SN 10/035,441
				Filing Date	Filed: January 4, 2002
				First Named Inventor	Naoaki YAMAGUCHI et al.
				Group Art Unit	1765
				Examiner Name	Anita Karen Alanko
				Attorney Docket Number	0756-7191
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Examiner Initials*	Cite No. ¹	U.S. Patent Document		Name of Patent or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number	Kind Code ² (if known)			
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Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ³
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Examiner Signature	<i>Calvin</i>	Date Considered	6.20.05
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